ELECTRICAL CHARACTERISTICS — continued ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic		Symbol	Min	Max	Unit
OFF CHARACTERISTICS (continued)					
Gate-Body Leakage Current, Forward (VGSF = 20 Vdc, VDS = 0)		IGSSF		100	nAdc
Gate-Body Leakage Current, Reverse (VGSR = 20 Vdc, VDS = 0)		IGSSR	1 - 1	100	nAdc
ON CHARACTERISTICS*			<u>'</u>		<u> </u>
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_{D} = 1 \text{ mA})$ $T_{J} = 100^{\circ}\text{C}$		V _{GS(th)}	2 1.5	4.5 4	Vdc
Static Drain-Source On-Resistance (VGS = 10 Vdc, ID = 6 Adc)		R _{DS(on)}		0.15	Ohm
Drain-Source On-Voltage (V _{GS} = 10 V) (I _D = 12 Adc) (I _D = 6 Adc, T _J = 100°C)		V _{DS(on)}	_	2 1.5	Vdc
Forward Transconductance (V _{DS} = 15 V, I _D = 6 A)		9FS	4		mhos
DRAIN-TO-SOURCE AVALANCHE STR	ESS CAPABILITY	· · · ·	-t J	-	
Unclamped Inductive Switching Energy See Figures 15 and 16 (Ip = 26 A, Vpb = 6 V, Tc = 25°C, Single Pulse, Non-repetitive) (Ip = 12 A, Vpb = 6 V, Tc = 25°C, P.W. \leq 200 μ s, Duty Cycle \leq 1%) (Ip = 4.8 A, Vpb = 6 V, Tc = 100°C, P.W. \leq 200 μ s, Duty Cycle \leq 1%)		WDSR		18 35 16	mJ
YNAMIC CHARACTERISTICS			<u> </u>		L
Input Capacitance	(V _{DS} = 25 V, V _{GS} = 0, f = 1 MHz) See Figure 11	C _{ISS}	T – T	500	pF
Output Capacitance		Coss	_	300	
Reverse Transfer Capacitance		C _{rss}	† †	100	
WITCHING CHARACTERISTICS* (TJ	= 100°C)				
Turn-On Delay Time	(V _{DD} = 25 V, I _D = 0.5 Rated I _D R _{gen} = 50 ohms) See Figure 18	td(on)	I	20	ns
Rise Time		tr	_	60	
Turn-Off Delay Time		td(off)	_	65	
Fall Time		tf	_	65	
Total Gate Charge	(V _{DS} = 0.8 Rated V _{DSS} , I _D = Rated I _D , V _{GS} = 10 V) See Figure 14	Og	12 (Typ)	17	пC
Gate-Source Charge		Qgs	6.5 (Typ)	_	
Gate-Drain Charge		$\Omega_{ extsf{gd}}$	5.5 (Typ)		
OURCE DRAIN DIODE CHARACTERIS	TICS*				
Forward On-Voltage	(I _{FM} = 0.5 Rated I _D ,	V _{SD}	1.7 (Typ)	2	Vdc
Forward Turn-On Time	$dig/dt = 100 \text{ A}/\mu\text{s}, \text{ V}_{GS} = 0$	ton	Limited by stray inductance		uctance
Reverse Recovery Time		t _{rr}	50 (Typ)	90	ns
ITERNAL PACKAGE INDUCTANCE (TO)-220)				
Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)		Ld	3 5 (Typ) 4.5 (Typ)	_	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad.)		L _S	7.5 (Typ)		

^{*}Pulse Test* Pulse Width = 300 μ s, Duty Cycle \leq 2%.

TYPICAL ELECTRICAL CHARACTERISTICS

MTP3055E

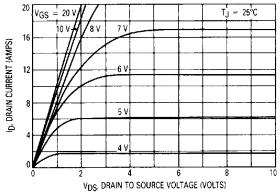


Figure 1. On-Region Characteristics

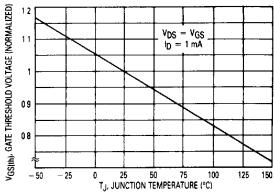


Figure 2. Gate-Threshold Voltage Variation With Temperature

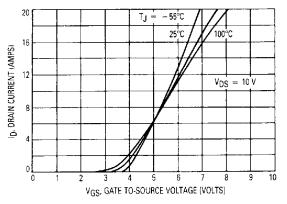


Figure 3. Transfer Characteristics

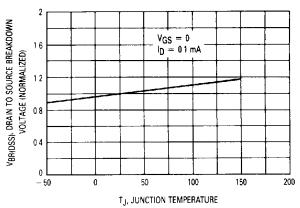


Figure 4. Breakdown Voltage Variation With Temperature

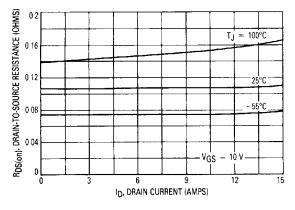


Figure 5. On-Resistance versus Drain Current

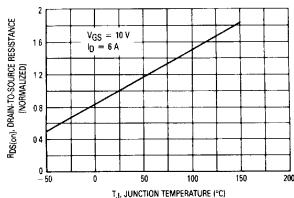


Figure 6. On-Resistance Variation With Temperature

SAFE OPERATING AREA INFORMATION

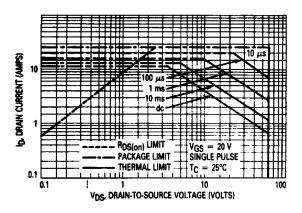


Figure 7. Maximum Rated Forward Biased Safe Operating Area

DRAIN CURRENT (AMPS) 30 20 T_{.1} ≤ 150°C ۵ 0 100 Δń សា VDS, DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 8. Maximum Rated Switching Safe Operating Area

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain-tosource voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, IDM and the breakdown voltage, V(BR)DSS. The switching SOA shown in Figure 8 is applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

The power averaged over a complete switching cycle must bé less than:

$$\frac{T_{J(max)} - T_{C}}{R_{\theta JC}}$$

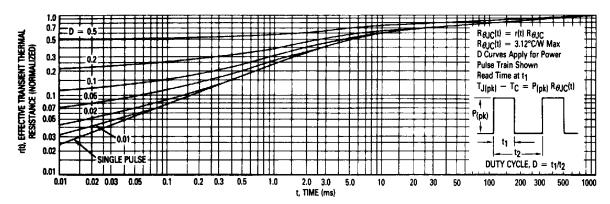


Figure 9. Thermal Response

COMMUTATING SAFE OPERATING AREA (CSOA)

The Commutating Safe Operating Area (CSOA) of Figure 12 defines the limits of safe operation for commutated source-drain current versus re-applied drain voltage when the source-drain diode has undergone forward bias. The curve shows the limitations of IFM and peak VR for a given commutation speed. It is applicable when waveforms similar to those of Figure 10 are present. Full or half-bridge PWM DC motor controllers are common applications requiring CSOA data.

The time interval tfrr is the speed of the commutation cycle. Device stresses increase with commutation speed, so tfrr is specified with a minimum value. Faster commutation speeds require an appropriate derating of IFM, peak VR or both. Ultimately, tfrr is limited primarily by device, package, and circuit impedances. Maximum device stress occurs during trr as the diode goes from conduction to reverse blocking.

VDS(pk) is the peak drain-to-source voltage that the device must sustain during commutation; IFM is the maximum forward source-drain diode current just prior to the onset of commutation.

 $V_{\mbox{\scriptsize R}}$ is specified at 80% of $V_{\mbox{\scriptsize (BR)DSS}}$ to ensure that the CSOA stress is maximized as IS decays from IRM to zero

RGS should be minimized during commutation. TJ has only a second order effect on CSOA.

Stray inductances, Li in Motorola's test circuit are assumed to be practical minimums.

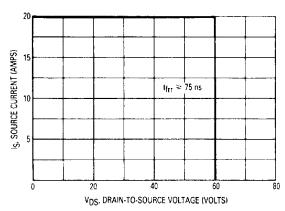


Figure 11. Commutating Safe Operating Area (CSOA)

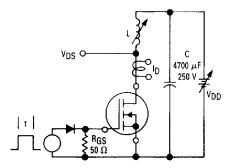


Figure 13. Unclamped Inductive Switching **Test Circuit**

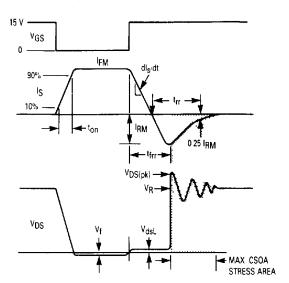


Figure 10. Commutating Waveforms

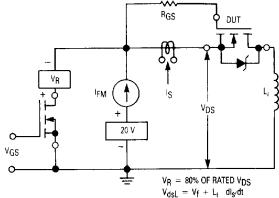


Figure 12. Commutating Safe Operating Area **Test Circuit**

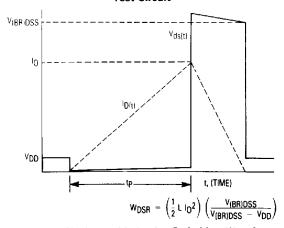
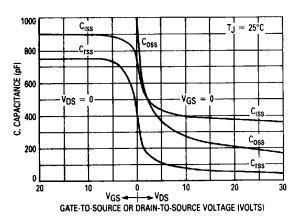


Figure 14. Unclamped Inductive Switching Waveforms



10 VDS = 25 VDS = 25 10 VDS = 25 10 PD = RATED ID =

Figure 15. Capacitance Variation

Figure 16. Gate Charge versus Gate-to-Source Voltage

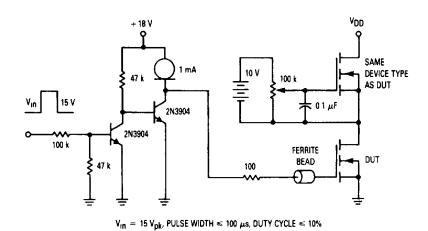


Figure 17. Gate Charge Test Circuit